



FINAL PRODUCT/PROCESS CHANGE NOTIFICATION
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26-MAY-2004

SUBJECT: ON Semiconductor Final Product/Process Change Notification #13478

TITLE: Addition of Tower Semiconductor Fab for Minigate(TM) Logic Products

EFFECTIVE DATE: 24-Jul-2004

AFFECTED CHANGE CATEGORY: ON Semiconductor Fab Site

AFFECTED PRODUCT DIVISION: Logic Products

ADDITIONAL RELIABILITY DATA: Available
Contact your local ON Semiconductor Sales Representative or
Ken Fergus <RRST50@onsemi.com>

SAMPLES: Contact your local ON Semiconductor Sales Representative
or Dianne Von Borstel <RPDR20@onsemi.com>

FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:
Contact Sales Representative or Nilda Lopez <R39140@onsemi.com>

NOTIFICATION TYPE:

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 60 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor Sales Office.

DESCRIPTION AND PURPOSE:

ON Semiconductor is pleased to announce expanded wafer capacity for MiniGate(TM) Logic products utilizing Tower Semiconductor. ON Semiconductor will implement this increase in capacity to support rapidly growing demand for these Logic products in an effort to assure our customers of ON Semiconductor's continued commitment to assured supply, on time delivery and continuous quality improvement.

The products will be redesigned using Tower Semiconductor's 0.6um design rules for their double layer metal, single polysilicon gate standard CMOS process. No performance changes are expected for these products. All product performance will meet the current datasheet specifications.

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Tower Semiconductor is a high volume Silicon supplier for flash memory, image sensors, mixed signal and standard CMOS products. They are located in Migdal Haemek, Israel, and are an ISO9001/QS9000 certified facility.

RELIABILITY DATA SUMMARY:

Reliability Test Results:

SC88A package, 1 lot ea. of 74VHC1GT00, 74VHC1G00, 74VHC1GT08:

Test	Conditions	Results (#fail/total SS)
High Temp Op Life	TA=150C for 504hrs	0/77, 0/77, 0/77
High Temp Bake	150C for 504 hrs	0/77, 0/77, 0/77
RSH	260C, 10 seconds	0/30, 0/30, 0/30
PC-Temp Cycle	-65/+150C for 500 cyc	0/77, 0/77, 0/77
PC-Autoclave	121C/100%RH/15psig for 96hrs	0/77, 0/77, 0/77
PC-HAST	131C/80%RH for 96 hrs	0/77, 0/77, 0/77
PC	168hrs 85C/85%, 3 IR at 260C	0/231, 0/231, 0/231

ELECTRICAL CHARACTERISTIC SUMMARY:

All product performance meets current datasheet specifications.

Data is available upon request.

CHANGED PART IDENTIFICATION: Devices shipped after WW29.

AFFECTED DEVICE LIST (WITHOUT SPECIALS):**PART**

MC74HC1G14DFT1
 MC74HC1G14DFT1G
 MC74HC1G14DFT2
 MC74HC1G14DFT2G
 MC74HC1G14DTT1
 MC74VHC1G132DF1G
 MC74VHC1G132DFT1
 MC74VHC1G132DFT2
 MC74VHC1G132DTT1
 NL17SZ08DFT2
 NL17SZ08DFT2G
 NLVHC1G14DFT2